

2SC4359

Silicon NPN triple diffusion planar type

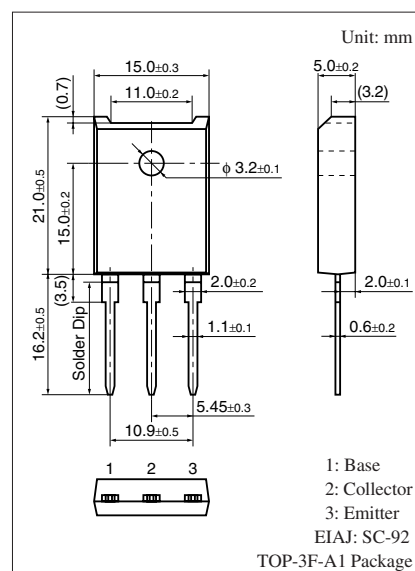
For high breakdown voltage high-speed switching

■ Features

- High-speed switching
- High collector-base voltage (Emitter open) V_{CBO}
- Wide safe operation area
- Satisfactory linearity of forward current transfer ratio h_{FE}

■ Absolute Maximum Ratings $T_C = 25^\circ\text{C}$

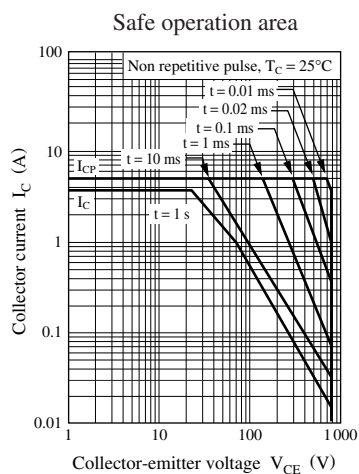
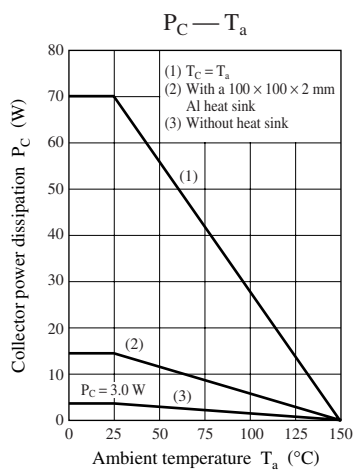
Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	V _{CBO}	900	V
Collector-emitter voltage (E-B short)	V _{CES}	900	V
Collector-emitter voltage (Base open)	V _{CEO}	800	V
Emitter-base voltage (Collector open)	V _{EBO}	7	V
Base current	I _B	1	A
Collector current	I _C	3	A
Peak collector current	I _{CP}	5	A
Collector power dissipation	P _C	70	W
		3.0	
	T _a = 25°C		
Junction temperature	T _j	150	°C
Storage temperature	T _{stg}	−55 to +150	°C



■ Electrical Characteristics $T_C = 25^\circ\text{C} \pm 2^\circ\text{C}$

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Collector-emitter voltage (Base open)	V_{CEO}	$I_C = 10\text{ mA}, I_B = 0$	800			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 900\text{ V}, I_E = 0$			50	μA
Emitter-base cutoff current (Collector open)	I_{EBO}	$V_{EB} = 7\text{ V}, I_C = 0$			50	μA
Forward current transfer ratio	h_{FE1}	$V_{CE} = 5\text{ V}, I_C = 0.1\text{ A}$	8			—
	h_{FE2}	$V_{CE} = 5\text{ V}, I_C = 0.8\text{ A}$	6			
Collector-emitter saturation voltage	$V_{CE(sat)}$	$I_C = 0.8\text{ A}, I_B = 0.16\text{ A}$			0.6	V
Base-emitter saturation voltage	$V_{BE(sat)}$	$I_C = 0.8\text{ A}, I_B = 0.16\text{ A}$			1.2	V
Transition frequency	f_T	$V_{CE} = 5\text{ V}, I_C = 0.15\text{ A}, f = 1\text{ MHz}$		10		MHz
Turn-on time	t_{on}	$I_C = 0.8\text{ A}$			0.7	μs
Storage time	t_{stg}	$I_{B1} = 0.16\text{ A}, I_{B2} = -0.32\text{ A}$			2.5	μs
Fall time	t_f	$V_{CC} = 250\text{ V}$			0.3	μs

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.



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